



Product Change Notification / LIAL-07RPOQ740

Date:

13-Dec-2022

Product Category:

Ethernet PHYs

PCN Type:

Manufacturing Change

Notification Subject:

CCB 5135 Final Notice: Qualification of a new lead frame with more Ag area on DAP surface prep for selected KSZ8081 and KSZ8091 device families available in 32L VQFN (5x5x0.9mm) package assembled at MTAI assembly site.

Affected CPNs:

[LIAL-07RPOQ740_Affected_CPN_12132022.pdf](#)

[LIAL-07RPOQ740_Affected_CPN_12132022.csv](#)

Notification Text:

PCN Status:Final Notification

PCN Type:Manufacturing Change

Microchip Parts Affected:Please open one of the files found in the Affected CPNs section.

Note: For your convenience Microchip includes identical files in two formats (.pdf and .xls)

Description of Change:Qualification of a new lead frame with more Ag area on DAP surface prep for selected KSZ8081 and KSZ8091 device families available in 32L VQFN (5x5x0.9mm) package assembled at MTAI assembly site.

Pre and Post Change Summary:

	Pre Change	Post Change
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LIAL-07RPOQ740 - CCB 5135 Final Notice: Qualification of a new lead frame with more Ag area on DAP surface prep for selected KSZ8081 and KSZ8091 device families available in 32L VQFN (5x5x0.9mm) package assembled at MTAI assembly site.

Affected Catalog Part Numbers (CPN)

KSZ8091RNBCA
KSZ8081MNXCA
KSZ8091MNXCA
KSZ8081MNXIA
KSZ8081RNBCA-TR
KSZ8091RNBCA-TR
KSZ8081MNXCA-TR
KSZ8091MNXCA-TR
KSZ8081RNBIA-TR
KSZ8091RNBIA-TR
KSZ8081MNXIA-TR
KSZ8091MNXIA-TR
SPNZ801174



MICROCHIP

QUALIFICATION REPORT SUMMARY
RELIABILITY LABORATORY

PCN# LIAL-07RPOQ740

Date
November 25, 2022

Qualification of a new lead frame with more Ag area on DAP surface prep for selected KSZ8081 and KSZ8091 device families available in 32L VQFN (5x5x0.9mm) package assembled at MTAI assembly site.



MICROCHIP PACKAGE QUALIFICATION REPORT

Purpose Qualification of a new lead frame with more Ag area on DAP surface prep for selected KSZ8081 and KSZ8091 device families available in 32L VQFN (5x5x0.9mm) package assembled at MTAI assembly site.

CN E000107074
QUAL ID R2200733 Rev A
MP CODE XKAA19PFAVA2
Part No. KSZ8051MNLV-VAO
Bonding No. BD-000677 Rev.02
CCB 5135

Package

Type 32L VQFN
Package size 5 x 5 x 0.9 mm

Lead Frame

Paddle size 150 x 150 mils
Material A194
Surface Ag selective plating (Add more Ag area)
Process Etched
Lead Lock Yes
Part Number 10103214

Material

Epoxy 3280
Wire Au/2N
Mold Compound G700LTD
Plating Composition Matte Sn



MICROCHIP PACKAGE QUALIFICATION REPORT

Manufacturing Information:

Assembly Lot No.	Wafer Lot No.	Date Code
MTAI230601567.000	DU02922523132.430	2219PAK
MTAI230601935.000	DU02922523132.430	2219Q83
MTAI230601936.000	DU02922523132.430	2219Q8D

Result

Pass Fail _____

32L VQFN (5x5x0.9 mm) assembled by MTAI pass reliability test per QCI-39000.
This package was qualified the Moisture/Reflow Sensitivity Classification Level 2 at 260°C
reflow temperature per IPC/JEDEC J-STD-020E standard.

PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS	Result	Remarks
Precondition Prior Perform Reliability Tests (At MSL Level 2)	Electrical Test: +25°C, 105°C and -43°C System: Chroma / SMB600	JESD22-A113	693(0)	0/693		Good Devices
	Bake 150°C, 24 hrs System: CHINEE	JIP/ IPC/JEDEC J-STD-020E		0/693		
	85°C/60%RH Moisture Soak 168 hrs. System: TABAI ESPEC Model PR-3SPH 3x Convection-Reflow 265°C max			0/693		
	System: Vitronics Soltec MR1243			0/693		
Electrical Test: +25°C and 105°C System: Chroma / SMB600		693(0)	0/693	Pass		
Temp Cycle	Stress Condition: -55°C to +125°C, 1000 Cycles System: TABAI ESPEC TSA-70H	JESD22-A104		0/231		Parts had been pre-conditioned at 260°C
	Electrical Test: +25°C and 105°C System: Chroma		231(0)	0/231	Pass	77 units / lot
	Bond Strength: Wire Pull (>2.50 grams) Bond Shear (>15.00 grams)		15(0) 15(0)	0/15 0/15	Pass Pass	
UNBIASED-HAST	Stress Condition: +130°C/85%RH, 96 hrs. System: HAST 6000X	JESD22-A118		0/231		Parts had been pre-conditioned at 260°C
	Electrical Test: +25°C System: SMB600		231(0)	0/231	Pass	77 units / lot
HAST	Stress Condition: +130°C/85%RH, 96 hrs. Bias Volt: 3.3 Volts System: HAST 6000X	JESD22-A110		0/231		Parts had been pre-conditioned at 260°C
	Electrical Test: +25°C and 105°C System: Chroma / SMB600		231(0)	0/231	Pass	77 units / lot

PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks
High Temperature Storage Life	Stress Condition: Bake 150°C, 500 hrs. System: SHEL LAB	JESD22-A103		0/45		
	Electrical Test: +25°C and 105°C System: Chroma / SMB600		45(0)	0/45	Pass	
Bond Strength Data Assembly	Wire Pull (>2.50 grams)	Mil. Std. 883-2011	30(0) Wires	0/30	Pass	
	Bond Shear (>15.00 grams)	CDF-AEC-Q100-001	30(0) bonds	0/30	Pass	